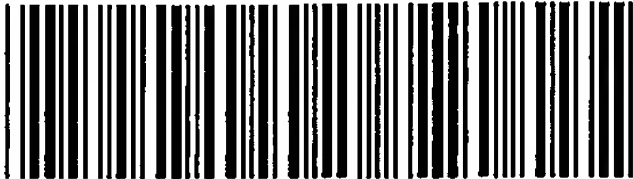


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/653,754	MEIER ET AL.	
	Examiner	Art Unit	
	Daniel Kim	2185	

SEARCHED			
Class	Subclass	Date	Examiner
711	128	6/10/2007	DK
711	118, 133	6/10/2007	DK
365	49, 50	6/10/2007	DK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search	6/10/2007	DK
Inventor Name Search for DP	6/10/2007	DK
IEEE Search	6/10/2007	DK
ACM Search	6/10/2007	DK